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| Notice of References Cited | Application/Control No. 10/825,340 | Applicant(s)/Patent Under Reexamination TSUJI ET AL. | |
| | Examiner Chia-Wei A. Chen | Art Unit 2622 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| * | A | US-6,164,842 | 12-2000 | Ohta et al. | 396/349 |
| * | B | US-6,086,266 | 07-2000 | Fujisaki, Yoshifumi | 396/448 |
| * | C | US-5,546,147 | 08-1996 | Baxter et al. | 396/349 |
| * | D | US-4,864,338 | 09-1989 | Wakabayashi, Hiroshi | 396/349 |
| * | E | US-5,761,556 | 06-1998 | Ichino, Kazushige | 396/349 |
| * | F | US-5,950,028 | 09-1999 | Ito, Toru | 396/349 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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